Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/742,341	HEIN ET AL.
Examiner	Art Unit
CUONG H. NGUYEN	3661

SEARCHED				
Class	Subclass	Date	Examiner	
701	36	3/17/2007	CHN	
307	10.1	3/17/2007	CHN	
200	314	3/17/2007	CHN	
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INTERFERENCE SEARCHED					
Class	Subclass	Date		Examiner	
701	36	3/17/2007		CHN	
307	10.1	3/17/	2007	CI	HN
200	314	3/17/	2007	CI	HN t
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
WEST/DERWENT ON CLOSEST REFS AND ALLOWABLE SUBJ. MATTER	3/17/2007	CHN
IEEE Xplore	3/17/2007	CHN
Inventors'names search .	3/17/2007	CHN